

## **LIST OF CONTRIBUTIONS TO NATIONAL AND INTERNATIONAL CONGRESSES 2018**

1. I. Vila, A. Garcia, E. Curras, G. Gomez, J. Gonzalez, J. Duarte, M. Fernandez, R. Jaramillo, S. Hidalgo.  
**An in-depth study of Inverse-LGAD sensors.**  
**13th "Trento" Workshop on Advanced Silicon Radiation Detectors; International**
2. S. Hidalgo; M. Carulla; A. Doblas; D. Flores; A. Merlos; G. Pellegrini; D. Quirion.  
**CNM activities on LGADs for ATLAS/CMS Timing Layers.**  
**32nd RD50 Workshop; International**
3. X. Jordà, X. Perpiñà, M. Vellvehi, D. Sánchez, A. García-Bediaga.  
**Thermal Characterization of SMD Packaged 650V GaN HEMTs Assembled in PCB Board.**  
**GaN Marathon 2.0; International**
4. M. Vellvehi, X. Perpiñà, D. Sánchez, P. Fernández-Martínez, D. Flores and X. Jordà.  
**Failure Analysis in Power Devices using Lock-in Infrared Thermography.**  
**Proceedings of Thermal, Mechanical and Multiphysics Simulation and Experiments in Micro-Electronics and Micro-Systems Conference (EuroSIME 2018)**
5. F. Torregrossa, Y. Spiegel, L. Roux, G. Sempere, G. Borvon, T. Wuebben, W. Schustereder, M. Jelinek, F. Morancho, P. Godignon, M. Zielinski.  
**Advantages and Challenges of Plasma Immersion Ion Implantation for Power Devices Manufacturing on Si, SiC and GaN using PULSION® Tool.**  
**22nd International Conference on Ion Implantation Technology (IIT), Würzburg, Germany, pp. 33-37, 2018**
6. M. Campos-Aranda, I Martín-Fernández, J.D. Alché.  
**LM approaches to the imaging and taxonomical identification of pollen intake by *Chrysoperla carnea* s.l. adults.**  
**Spanish Portuguese Meeting for Advanced Optical Microscopy (SPAOM2018). International**
7. I. Martín-Fernández, X. Illa, E. Masvidal-Codina, E. Prats-Alfonso, A. Guimerà-Brunet, R. Villa, P. Godignon.  
**Integration of CVD graphene for wafer scale fabrication of Devices.**  
**Graphene Week 2018**

8. E. Masvidal-Codina, X. Illa, M. Dasilva, A. Bonaccini, E. Prats-Alfonso, J. Martínez-Aguilar, C. Hébert, E. Del Corro Garcia, I. Martín-Fernandez, J. Bousquet, R. Villa, M. Sanchez-Vives, J. A. Garrido, A. Guimerà-Brunet.  
**Graphene transistors for ultra-slow frequency (< 0.1Hz) in vivo neural recording.**  
**Graphene 2018**
9. V. Soler, M. Cabello, V. Banu, J. Montserrat, J. Rebollo, P. Godignon, E. Bianda, L. Knoll, L. Kranz, A. Mihaila.  
**Dynamic characterization and robustness test of high voltage SiC MOSFETs.**  
**European Conference on Silicon Carbide & Related Materials (ECSCRM)**
10. M. Cabello, V. Soler, D. Haasmann, J. Montserrat, J. Rebollo, P. Godignon.  
**Evidence of channel mobility anisotropy on 4H-SiC MOSFETs with low interface trap density.**  
**European Conference on Silicon Carbide & Related Materials (ECSCRM)**
11. V. Soler, M. Cabello, V. Banu, J. Montserrat, J. Rebollo, P. Godignon.  
**Temperature behavior of complementary SiC MOSFETs for CMOS integration.**  
**European Materials Research Society (E-MRS) Fall Meeting**
12. V. Soler, M. Cabello, V. Banu, J. Montserrat, E. Bianda, L. Knoll, L. Kranz, A. Mihaila, J. Rebollo, P. Godignon.  
**Caracterización dinámica y tests de robustez de MOSFETs de SiC de alta tensión.**  
**IEEE 25th Seminario Anual de Automática, Electrónica Industrial e Instrumentación (SAAEI)**
13. P. Godignon, G. Rius, M. Cabello, V. Soler, J. Rebollo, J. Montserrat.  
**Gallium Oxide as the next semiconductor for power devices.**  
**IEEE 25th Seminario Anual de Automática, Electrónica Industrial e Instrumentación (SAAEI)**
14. Maria Cabello, Victor Soler, Lars Knoll, Josep Montserrat, Jose Rebollo, Andrei Mihaila and Philippe Godignon.  
**Comparative study of boron doped gate oxide impact on 4H and 6H-SiC n-MOSFETs**  
**European Materials Research Society (E-MRS) Fall Meeting**
15. C. Couso, D. Flores, S. Hidalgo, D. Quirion, M. Ullán.  
**Multi-Ring JFET Structure for Harsh Radiation Applications.**  
**14th Int. Seminar on Power Semiconductors (ISPS'18)**
16. C. Couso, D. Flores, S. Hidalgo, D. Quirion, M. Ullán.  
**Novel Radiation-Hard JFET Device Based on 3D Multi-Ring Cells.**  
**12ª Conferencia de Dispositivos Electrónicos (CDE'18)**

17. V. Banu, J. Montserrat, X. Jordà, P. Godignon.  
**Surface Recombination Evaluation in Bipolar Junction Transistors by Combined Electro-Optical Method.**  
**41th International Semiconductor Conference (CAS 2018)**
18. V. Banu, P. Godignon.  
**The Wide Band-gap Semiconductors, a New Trend of Power Semiconductor Devices Development.**  
**Forum Romanians in micro-and nanoelectronics**
19. X. Jordà, A. Avila, A. Garcia-Bediaga, X. Perpiñà, M. Vellvehi.  
**Analysis of Natural Convection Cooling Solutions For GaN HEMT Transistors. European Power Electronics (EPE'18-ECCE EUROPE)**
20. A. Avila, A. Garcia-Bediaga, F. González, X. Jordà, X. Perpiñà, A. Rojas.  
**Thermal Performance Analysis of GaN-Based High-Power Converters.**  
**European Power Electronics (EPE'18-ECCE EUROPE)**